

January 2001

FQP13N10

100V N-Channel MOSFET

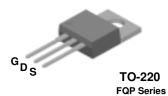
General Description

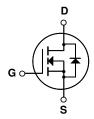
These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand a high energy pulse in the avalanche and commutation modes. These devices are well suited for low voltage applications such as audio amplifier, high efficiency switching DC/DC converters, and DC motor control.

Features

- 12.8A, 100V, $R_{DS(on)}$ = 0.18 Ω @V_{GS} = 10 V Low gate charge (typical 12 nC)
- Low Crss (typical 20 pF)
- Fast switching
- 100% avalanche tested
- · Improved dv/dt capability
- 175°C maximum junction temperature rating





Absolute Maximum Ratings T_C = 25 °C unless otherwise noted

Symbol	Parameter		FQP13N10	Units	
V _{DSS}	Drain-Source Voltage		100	V	
I _D	Drain Current - Continuous (T _C = 25 ℃)		12.8	Α	
	- Continuous (T _C = 100 °C)		9.05	Α	
I _{DM}	Drain Current - Pulsed	(Note 1)	51.2	Α	
V _{GSS}	Gate-Source Voltage		± 25	V	
E _{AS}	Single Pulsed Avalanche Energy	(Note 2)	95	mJ	
I _{AR}	Avalanche Current	(Note 1)	12.8	Α	
E _{AR}	Repetitive Avalanche Energy	(Note 1)	6.5	mJ	
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	6.0	V/ns	
P _D	Power Dissipation (T _C = 25 °C)		65	W	
	- Derate above 25 ℃		0.43	W/°C	
T _J , T _{STG}	Operating and Storage Temperature Range		-55 to +175	℃	
T _L	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds		300	℃	

Thermal Characteristics

Symbol	Parameter	Тур	Max	Units
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case		2.31	%C\M
$R_{\theta CS}$	Thermal Resistance, Case-to-Sink	0.5		%C\M
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient		62.5	°C/W

Symbol	Parameter	Test Conditions		Min	Тур	Max	Units
Off Cha	aracteristics						
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		100			V
ΔBV _{DSS} / ΔΤ _J	Breakdown Voltage Temperature Coefficient	$I_D = 250 \mu A$, Referenced	to 25℃		0.09	1	V/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 100 V, V _{GS} = 0 V				1	μΑ
		V _{DS} = 80 V, T _C = 150 °C				10	μΑ
I _{GSSF}	Gate-Body Leakage Current, Forward	V _{GS} = 25 V, V _{DS} = 0 V				100	nA
I _{GSSR}	Gate-Body Leakage Current, Reverse	$V_{GS} = -25 \text{ V}, V_{DS} = 0 \text{ V}$				-100	nA
On Cha	racteristics						
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = 250 \mu A$		2.0		4.0	V
R _{DS(on)}	Static Drain-Source On-Resistance	V _{GS} = 10 V, I _D = 6.4 A			0.142	0.18	Ω
9 _{FS}	Forward Transconductance	$V_{DS} = 40 \text{ V}, I_{D} = 6.4 \text{ A}$	(Note 4)		6.8		S
	Input Capacitance Output Capacitance	$V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V},$ f = 1.0 MHz			100	450 130	pF pF
C _{oss}	Output Capacitance				100	130	pF
C _{rss}	Reverse Transfer Capacitance				20	25	pF
Switchi	ing Characteristics						
t _{d(on)}	Turn-On Delay Time	$V_{DD} = 50 \text{ V}, I_{D} = 12.8 \text{ A},$ $R_{G} = 25 \Omega$			5	20	ns
t _r	Turn-On Rise Time				55	120	ns
t _{d(off)}	Turn-Off Delay Time				20	50	ns
t _f	Turn-Off Fall Time		(Note 4, 5)		25	60	ns
Qg	Total Gate Charge	V _{DS} = 80 V, I _D = 12.8 A,			12	16	nC
Q _{gs}	Gate-Source Charge	V _{GS} = 10 V			2.5		nC
Q _{gd}	Gate-Drain Charge	(Note 4, 5			5.1		nC
	Source Diode Characteristics a	nd Maximum Ratings	.				
I _S	Maximum Continuous Drain-Source Diode Forward Current				12.8	Α	
I _{SM}	Maximum Pulsed Drain-Source Diode Forward Current				51.2	Α	
V _{SD}	Drain-Source Diode Forward Voltage	V _{GS} = 0 V, I _S = 12.8 A				1.5	V
t _{rr}	Reverse Recovery Time	$V_{GS} = 0 \text{ V, } I_S = 12.8 \text{ A,}$ $dI_F / dt = 100 \text{ A/}\mu\text{s}$ (Note 4)			72		ns
Q _{rr}	Reverse Recovery Charge				0.17		μC

- **Notes:**1. Repetitive Rating : Pulse width limited by maximum junction temperature 2. L = 0.87mH, I_{AS} = 12.8A, V_{DD} = 25V, R_G = 25 Ω , Starting T_J = 25 °C 3. I_{SD} = 12.8A, di/dt \leq 300A/μs, V_{DD} \leq BV_{DSS}, Starting T_J = 25 °C 4. Pulse Test : Pulse width \leq 300μs, Duty cycle \leq 2% 5. Essentially independent of operating temperature

Typical Characteristics

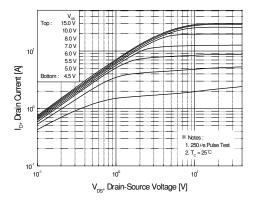


Figure 1. On-Region Characteristics

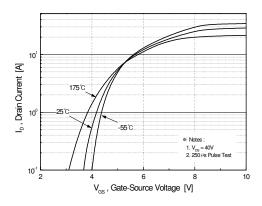


Figure 2. Transfer Characteristics

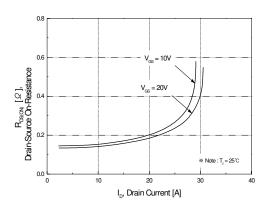


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

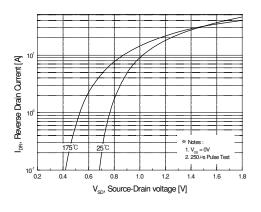


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

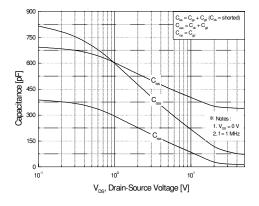


Figure 5. Capacitance Characteristics

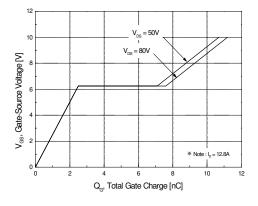


Figure 6. Gate Charge Characteristics

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Typical Characteristics (Continued)

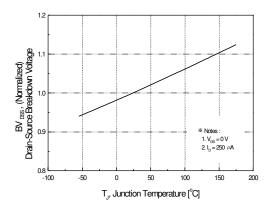
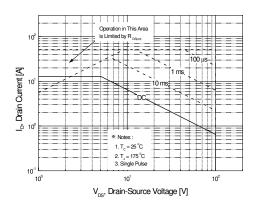


Figure 7. Breakdown Voltage Variation vs. Temperature

Figure 8. On-Resistance Variation vs. Temperature



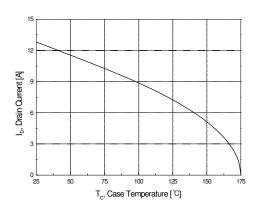


Figure 9. Maximum Safe Operating Area

Figure 10. Maximum Drain Current vs. Case Temperature

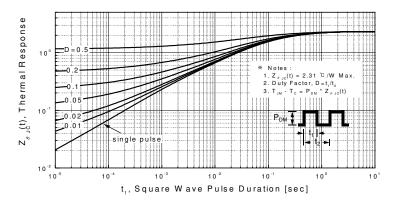
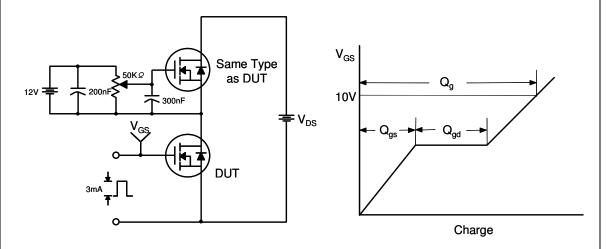


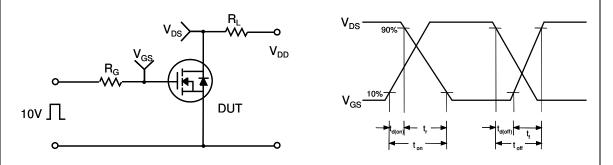
Figure 11. Transient Thermal Response Curve

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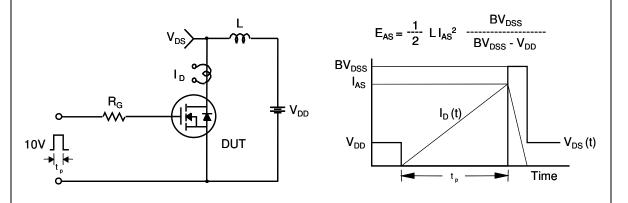
Gate Charge Test Circuit & Waveform



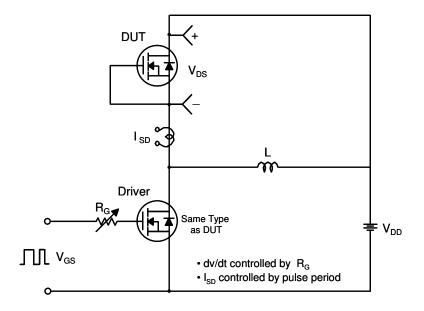
Resistive Switching Test Circuit & Waveforms

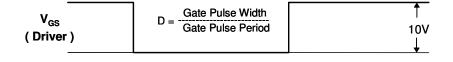


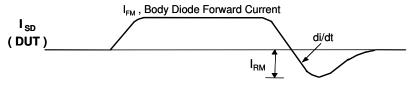
Unclamped Inductive Switching Test Circuit & Waveforms



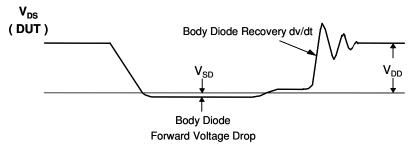
Peak Diode Recovery dv/dt Test Circuit & Waveforms

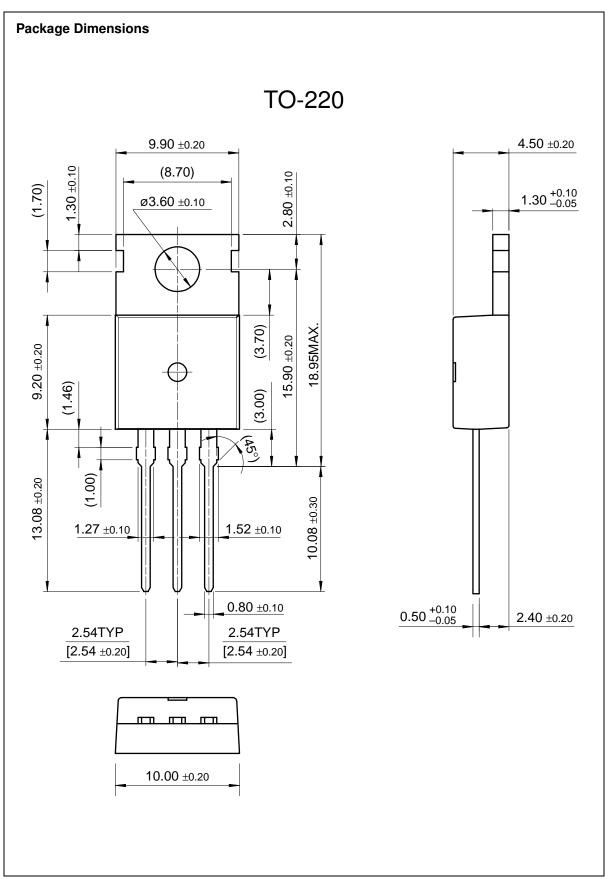






Body Diode Reverse Current





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